Applicant(s)/Patent Under Application/Control No. Reexamination 09/493,601 DENNIS ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1652 Tekchand Saidha **U.S. PATENT DOCUMENTS** Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY US-5,965,423 10-1999 Hillman et al. 435/198 Α US-В US-С US-D US-Ε US-F US-G USн US-US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U Sequence search alignment between Applicants' SEQ ID NO: 1 and Accession No. AF052112. Wang et al. [BBA 1437:157-169 (1999)]. W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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